

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/738,397	JIN ET AL.	
Examiner	Art Unit	
Rinh X Tran	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
438	705	8/7/2006	ВТ		
438	724	8/7/2006	вт		
438	744	8/7/2006	ВТ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	8/7/2006	вт
438/714 text search only	8/7/2006	вт
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